

- 1) For the conversion of raw data into structure factors and their standard deviations:

What are the units of F_o^2 ? (i.e. the observed, unscaled structure factor intensity)

What are the units of $F_{(hkl)}^2$? (i.e. the calculated structure factor, unscaled)

What are the units of the unscaled F_c^2 ?

How do we scale our observations into what we need?

What are the units of the standard deviation of F_o^2 ?

What are the units of the variance of F_o^2 ?

Why do we add variances and not standard deviations?

Why is there a difference in the dependence of the ratio (r) of time (or pixels) for raw count collection (P) versus background (B) when calculating I versus $\sigma(I)$?
[e.g. if $I = P - rB$ what is the dependence of $\sigma(I)$ on r ?]

What is the relative size of I versus $\sigma(I)$ typical of X-ray structures?

- 2) Note that for the general expression for the structure factor of a reflection,

$$F_{hkl} = \sum_{j=1}^N f_j e^{2\pi i(hx_j + ky_j + lz_j)}$$

We can equally well write $F_{hkl} = A + iB$.

For the space groups:

- Cc
- $P2_12_12_1$
- Pnma

Write the simplified forms of A and B by suitably combining those terms involving atom positions related by symmetry.

- Does this simplified form of the structure factor predict any systematic absences?
- Which reflections are of equal intensity? [Note that the problem applies equally well when we consider the integral equation for F_{hkl} in terms of the continuous electron-density function $\rho(x, y, z)$.]
- Is your answer to ii) consistent with the Laue symmetry of the space group?